

参考資料



SN54SC4T08-SEP

JAJSQE6A - MAY 2023 - REVISED AUGUST 2023

SN54SC4T08-SEP 耐放射線特性、1.2V~5.5V、クワッド 2 入力正論理 AND ゲー ト、変換機能内蔵

1 特長

- VID (Vendor Item Drawing) V62/23620 が利用可能
- 吸収線量 (TID) 耐性 = 30krad (Si)
 - すべてのウェハー・ロットについての 30krad(Si) ま での吸収線量耐性放射線ロット受け入れテスト (TID RLAT)
- シングル・イベント効果 (SEE) 特性:
 - シングル・イベント・ラッチアップ (SEL) 耐性:線エ ネルギー付与 (LET) = 43MeV-cm2/mg
 - シングル・イベント過渡 (SET) 特性:43MeVcm2/mg
- 幅広い動作範囲:1.2V~5.5V
- 5/3.3/2.5/1.8/1.2V V_{CC} Ø 単電源変換ゲート
 - TTL 互換入力:
 - 昇圧変換:
 - 1.8V 1.2V からの入力
 - 2.5V 1.8V からの入力
 - 3.3V 1.8V、2.5V からの入力
 - 5.0V 2.5V、3.3V からの入力
 - 降圧変換:
 - 1.2V 1.8V, 2.5V, 3.3V, 5.0V からの入力
 - 1.8V 2.5V、3.3V、5.0V からの入力
 - 2.5V 3.3V、5.0V からの入力
 - 3.3V 5.0V からの入力
- 5.5V 耐圧入力ピン
- 5V で最大 25mA の出力駆動能力
- JESD 17 準拠で 250mA 超のラッチアップ性能
- 宇宙向け強化プラスチック (SEP)
 - 管理されたベースライン
 - 金ボンド・ワイヤ
 - NiPdAu リード仕上げ
 - 単一のアセンブリ/テスト施設
 - 単一の製造施設
 - 軍用温度範囲:-55℃~125℃
 - 長い製品ライフ・サイクル
 - 製品変更通知期間 (PCN) の延長
 - 製品のトレーサビリティ
 - NASA ASTM E595 アウトガス仕様に適合

2 アプリケーション

- デジタル信号のイネーブルまたはディスエーブル
- インジケータ LED の制御
- 通信モジュールとシステム・コントローラ間の変換

3 概要

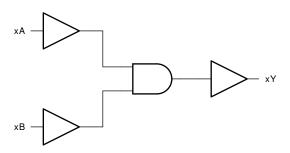
SN54SC4T08-SEP には、4 つの独立した 2 入力 AND ゲートが内蔵されています。各ゲートはブール関数 Y = A × B を正論理で実行します。出力レベルは電源電圧 (V_{CC}) を基準としており、1.2V、1.8V、2.5V、3.3V、5V の CMOS レベルをサポートしています。

入力は、低電圧 CMOS 入力の昇圧変換 (例:1.2V 入力 から 1.8V 出力、1.8V 入力から 3.3V 出力) をサポートす るため、低スレッショルド回路を使って設計されています。 また、5V 耐圧の入力ピンにより、降圧変換 (例:3.3V から 2.5V 出力) が可能です。

パッケージ情報

部品番号	パッケージ ⁽¹⁾	パッケージ・サイズ (2)	本体サイズ (公称) ⁽³⁾
SN54SC4T08-SEP	PW (TSSOP, 14)	5mm × 6.4mm	5mm × 4.4mm

- 利用可能なすべてのパッケージについては、データシートの末尾 にある注文情報を参照してください。
- パッケージ・サイズ (長さ×幅) は公称値であり、該当する場合はピ ンも含まれます。
- 本体サイズ (長さ×幅) は公称値であり、ピンは含まれません。



概略ロジック図



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4 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

С	Changes from Revision * (May 2023) to Revision A (August 2023)	Page
•	データシートのステータスを以下のように変更:「事前情報」から <i>「量産データ」へ</i>	1

Product Folder Links: SN54SC4T08-SEP



5 Pin Configuration and Functions

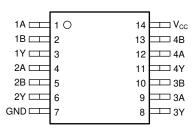


図 5-1. PW Package, 14-Pin TSSOP (Top View)

表 5-1. Pin Functions

PIN		- TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.	- ITPE(")	DESCRIPTION
1A	1	I	Channel 1, Input A
1B	2	I	Channel 1, Input B
1Y	3	0	Channel 1, Output Y
2A	4	I	Channel 2, Input A
2B	5	Į	Channel 2, Input B
2Y	6	0	Channel 2, Output Y
GND	7	G	Ground
3Y	8	0	Channel 3, Output Y
3A	9	I	Channel 3, Input A
3B	10	Į	Channel 3, Input B
4Y	11	0	Channel 4, Output Y
4A	12	I	Channel 4, Input A
4B	13	I	Channel 4, Input B
V _{CC}	14	Р	Positive Supply

⁽¹⁾ I = Input, O = Output, I/O = Input or Output, G = Ground, P = Power.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	7	V
Vo	Voltage range applied to any outp	Voltage range applied to any output in the high-impedance or power-off state ⁽²⁾		7	V
Vo	Output voltage range ⁽²⁾	Output voltage range ⁽²⁾		V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < -0.5 V		-20	mA
I _{OK}	Output clamp current	V_{O} < -0.5 V or V_{O} > V_{CC+} 0.5 V		±20	mA
Io	Continuous output current	V _O = 0 to V _{CC}		±25	mA
	Continuous output current through	Continuous output current through V _{CC} or GND		±50	mA
T _{stg}	Storage temperature	Storage temperature			°C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD) Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	\/	
	discharge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±1000	v

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

Spec	Description	Condition	MIN	MAX	UNIT
V _{CC}	Supply voltage	'	1.2	5.5	V
V _I (1)	Input voltage		0	5.5	V
Vo	Output voltage		0	V _{CC}	V
		V _{CC} = 1.2 V to 1.3 V	0.78		
		V _{CC} = 1.65 V to 2 V	1.1		
V_{IH}	High-level input voltage	V _{CC} = 2.25 V to 2.75 V	1.28		V
		V _{CC} = 3 V to 3.6 V	1.45		
		V _{CC} = 4.5 V to 5.5 V	2		
		V _{CC} = 1.2 V to 1.3 V		0.18	
		V _{CC} = 1.65 V to 2 V		0.5	
V_{IL}	Low-Level input voltage	V _{CC} = 2.25 V to 2.75 V	-	0.65	V
		V _{CC} = 3 V to 3.6 V		0.75	
		V _{CC} = 4.5 V to 5.5 V		0.85	
		V _{CC} = 1.6 V to 2 V		±3	
ı	Output ourrent	V _{CC} = 2.25 V to 2.75 V		±7	т Л
l _o	Output current	V _{CC} = 3.3 V to 3.6 V		±15	mA
		V _{CC} = 4.5 V to 5.5 V		±25	
Δt/Δν	Input transition rise or fall rate	V _{CC} = 1.2 V to 5.5 V		20	ns/V
T _A	Operating free-air temperature		-55	125	°C

⁽¹⁾ All inputs of the device must be held at a valid high or low state for proper device operation. Refer to the *Feature Description* section under *SCxT Enhanced Input Voltage* for details.

6.4 Thermal Information

		SN54SC4T08-SEP	
	THERMAL METRIC ⁽¹⁾	PW (TSSOP)	UNIT
		14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	147.7	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	77.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	90.9	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	27.2	°C/W
Y_{JB}	Junction-to-board characterization parameter	90.2	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



6.5 Electrical Characteristics

over operating free-air temperature range; typical ratings measured at T_A = 25°C (unless otherwise noted).

PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
	I _{OH} = -50 μA	1.2 V to 5.5 V	V _{CC} -0.2			
	I _{OH} = -1 mA	1.2 V	0.8	1.1 ⁽¹⁾		
	I _{OH} = -2 mA	1.65 V to 2 V	1.21	1.7 ⁽¹⁾		
V_{OH}	I _{OH} = -3 mA	2.25 V to 2.75 V	1.93	2.4 ⁽¹⁾		V
	I _{OH} = -5.5 mA	3 V to 3.6 V	2.49	3.08(1)		
	I _{OH} = -8 mA	4.5 V to 5.5 V	3.95	4.65 ⁽¹⁾		
	I _{OH} = -24 mA	4.5 V to 5.5 V	3.15			
	I _{OL} = 50 μA	1.2 V to 5.5 V			0.1	
	I _{OL} = 1 mA	1.2 V			0.2	
	I _{OL} = 2 mA	1.65 V to 2 V		0.1(1)	0.25	
V_{OL}	I _{OL} = 3 mA	2.25 V to 2.75 V		0.1(1)	0.2	V
	I _{OL} = 5.5 mA	3 V to 3.6 V		0.2(1)	0.25	
	I _{OL} = 8 mA	4.5 V to 5.5 V		0.3(1)	0.35	
	I _{OL} = 24 mA	4.5 V to 5.5 V			0.75	
I _I	V _I = 0 V or V _{CC}	0 V to 5.5 V		±0.1	±1	μA
I _{cc}	V _I = V _{CC} or GND, I _O = 0	1.2 V to 5.5 V		2	93	μA
Al	One input at 0.3 V or 3.4 V, other inputs at 0 or V_{CC} , $I_{O} = 0$	5.5 V		1.35	1.5	mA
ΔI _{CC}	One input at 0.3 V or 1.1 V, other inputs at 0 or V_{CC} , $I_O = 0$	1.8 V		5	68	μΑ
C _I	V _I = V _{CC} or GND	5 V		3	5	pF
C _{PD} (2) (3)	C _L = 50 pF, F = 10 MHz	1.2 V to 5.5 V		11	25	pF

- Typical value at nearest nominal voltage (1.8 V, 2.5 V, 3.3 V, and 5 V)
- (2) C_{PD} is used to determine the dynamic power consumption, per channel.
 (3) P_D= V_{CC}² × F_I × (C_{PD}+ C_L) where F_I= input frequency, C_L= output load capacitance, V_{CC}= supply voltage.

6.6 Switching Characteristics

over operating free-air temperature range; typical ratings measured at T_A = 25°C (unless otherwise noted).

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	V _{CC}	MIN	TYP	MAX	UNIT
t _{PHL}	A or B	Υ	C = 15 pE		;	38.33	117.5	nS
t _{PLH}	A or B	Υ	C _L = 15 pF	1.2 V		26.6	102.8	nS
t _{PHL}	A or B	Υ	C = 50 pF	1.2 V		42.37	137.2	nS
t _{PLH}	A or B	Υ	-C _L = 50 pF			30.97	115.2	nS
t _{PHL}	A or B	Υ	0 - 45 - 5			14.9	38.1	nS
t _{PLH}	A or B	Υ	-C _L = 15 pF	4.0.1/		9.81	33.7	nS
t _{PHL}	A or B	Υ	1.8 V		16.54	43.6	nS	
t _{PLH}	A or B	Υ	C _L = 50 pF			11.73	38.0	nS
t _{PHL}	A or B	Υ	C = 15 pF			9.31	22.6	nS
t _{PLH}	A or B	Υ	C _L = 15 pF	0.514		5.59	20.2	nS
t _{PHL}	A or B	Υ	0 - 50 - 5	-2.5 V		10.36	26.4	nS
t _{PLH}	A or B	Υ	-C _L = 50 pF			7.16	23.1	nS

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6.6 Switching Characteristics (continued)

over operating free-air temperature range; typical ratings measured at $T_A = 25$ °C (unless otherwise noted).

PARAMETER	FROM (INPUT)	то (оитрит)	LOAD CAPACITANCE	V _{cc}	MIN TYP	MAX	UNIT
t _{PHL}	A or B	Υ	C = 15 pE		7.17	16.1	nS
t _{PLH}	A or B	Υ	C _L = 15 pF	3.3 V	4.15	14.6	nS
t _{PHL}	A or B	Υ	0 50 - 5	$C_1 = 50 \text{ pF}$	7.84	19.0	nS
t _{PLH}	A or B	Υ	CL = 50 pr		5.24	16.7	nS
t _{PHL}	A or B	Υ	C = 15 pE	5.1/	5.62	10.6	nS
t _{PLH}	A or B	Υ	-C _L = 15 pF		3.06	9.7	nS
t _{PHL}	A or B	Υ	C = 50 pF	5 V	6.11	13.0	nS
t _{PLH}	A or B	Υ	C _L = 50 pF		3.76	11.4	nS

6.7 Noise Characteristics

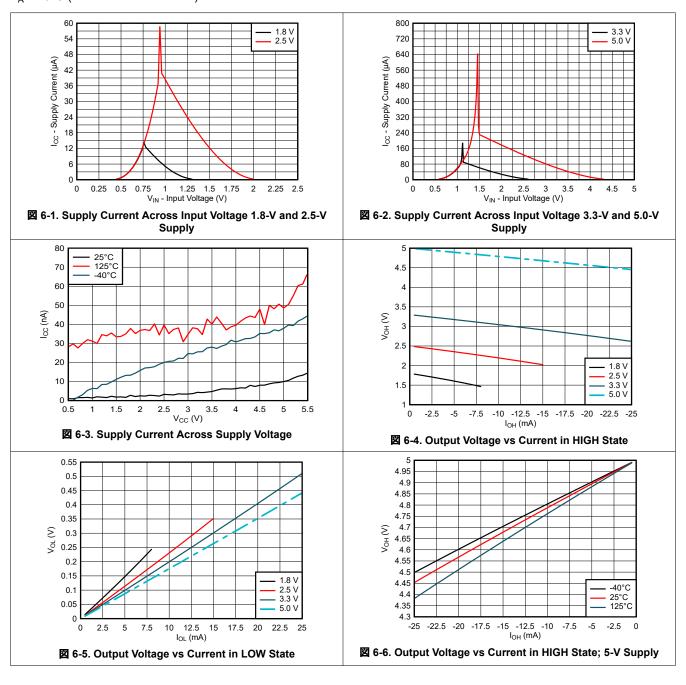
VCC = 5 V, CL = 50 pF, TA = 25°C

PARAMETER	DESCRIPTION	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		1	1.2	V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}	-0.8	-0.3		V
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}	4.4	5		V
V _{IH(D)}	High-level dynamic input voltage	2.1			V
$V_{IL(D)}$	Low-level dynamic input voltage			0.5	V



6.8 Typical Characteristics

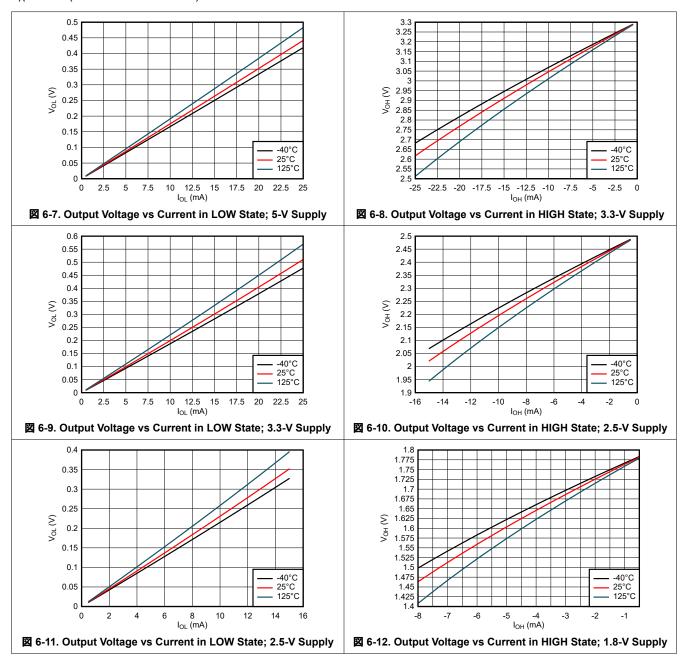
T_A = 25°C (unless otherwise noted)





6.8 Typical Characteristics (continued)

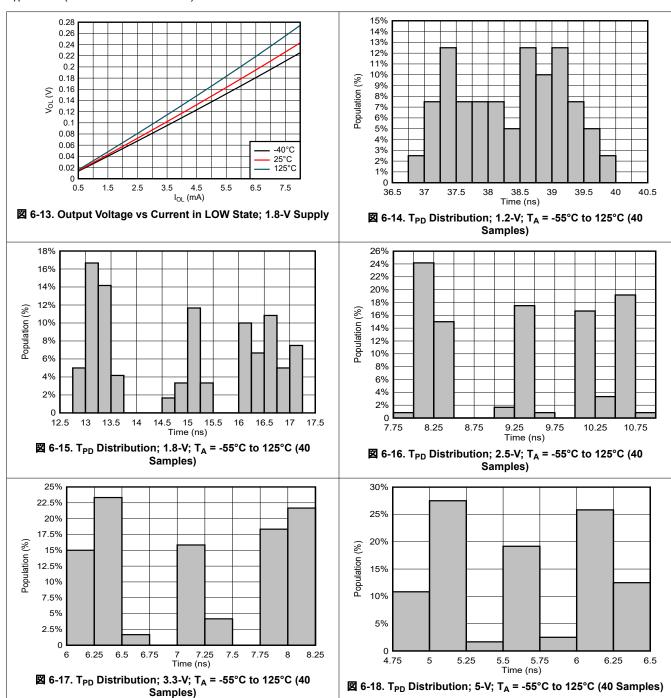
T_A = 25°C (unless otherwise noted)





6.8 Typical Characteristics (continued)

T_A = 25°C (unless otherwise noted)



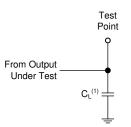


7 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_t < 2.5 \text{ ns}$.

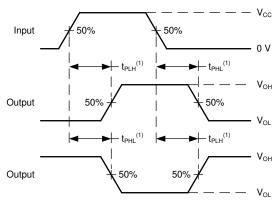
For clock inputs, f_{max} is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



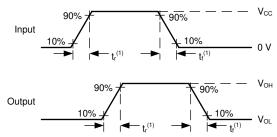
(1) C_L includes probe and test-fixture capacitance.

図 7-1. Load Circuit for Push-Pull Outputs



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

図 7-2. Voltage Waveforms Propagation Delays



(1) The greater between t_r and t_f is the same as t_t.

図 7-3. Voltage Waveforms, Input and Output Transition Times

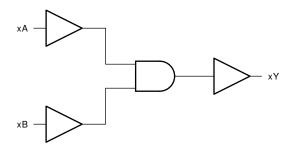


8 Detailed Description

8.1 Overview

The SN54SC4T08-SEP contains four independent 2- input AND Gates. Each gate performs the Boolean function $Y = A \times B$ in positive logic. The output level is referenced to the supply voltage (V_{CC}) and supports 1.2-V, 1.8-V, 2.5-V, 3.3-V, and 5-V CMOS levels.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Balanced CMOS Push-Pull Outputs

This device includes balanced CMOS push-pull outputs. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

Unused push-pull CMOS outputs should be left disconnected.

8.3.2 Clamp Diode Structure

As 🗵 8-1 shows, the outputs to this device have both positive and negative clamping diodes, and the inputs to this device have negative clamping diodes only.

注意

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

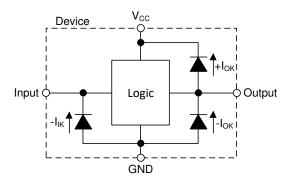


図 8-1. Electrical Placement of Clamping Diodes for Each Input and Output

8.3.3 SCxT Enhanced Input Voltage

The SN54SC4T08-SEP belongs to TI's SCxT family of logic devices with integrated voltage level translation. This family of devices was designed with reduced input voltage thresholds to support up-translation, and inputs tolerant of signals with up to 5.5 V levels to support down-translation. The output voltage will always be referenced to the supply voltage (V_{CC}), as described in the *Electrical Characteristics* table. For proper functionality, input signals must remain at or below the specified $V_{IH(MIN)}$ level for a HIGH input state, and at or below the specified $V_{IL(MAX)}$ for a LOW input state. \boxtimes 8-2 shows the typical V_{IH} and V_{IL} levels for the SCxT family of devices, as well as the voltage levels for standard CMOS devices for comparison.

The inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using Ohm's law $(R = V \div I)$.

The inputs require the input signals to transition between valid logic states quickly, as defined by the input transition time or rate in the *Recommended Operating Conditions* table. Failing to meet this specification will result in excessive power consumption and can cause oscillations. More details can be found in the *Implications of Slow or Floating CMOS Inputs* application report.

Do not leave inputs floating at any time during operation. Unused inputs must be terminated at V_{CC} or GND. If a system will not be actively driving an input at all times, a pull-up or pull-down resistor can be added to provide a valid input voltage during these times. The resistor value will depend on multiple factors; however, a $10-k\Omega$ resistor is recommended and will typically meet all requirements.

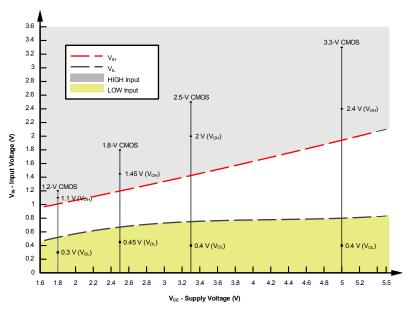


図 8-2. SCxT Input Voltage Levels

8.3.3.1 Down Translation

Signals can be translated down using the SN54SC4T08-SEP. The voltage applied at the V_{CC} will determine the output voltage and the input thresholds as described in the *Recommended Operating Conditions* and *Electrical Characteristics* tables.

When connected to a high-impedance input, the output voltage will be approximately V_{CC} in the HIGH state, and 0 V in the LOW state. Ensure that the input signals in the HIGH state are between $V_{IH(MIN)}$ and 5.5 V, and input signals in the LOW state are lower than $V_{IL(MAX)}$ as shown in \boxtimes 8-2.

For example, standard CMOS inputs for devices operating at 5.0 V, 3.3 V or 2.5 V can be down-translated to match 1.8 V CMOS signals when operating from 1.8-V V_{CC} .

Down Translation Combinations are as follows:

- 1.8-V V_{CC} Inputs from 2.5 V, 3.3 V, and 5.0 V
- 2.5-V V_{CC} Inputs from 3.3 V and 5.0 V
- 3.3-V V_{CC} Inputs from 5.0 V

8.3.3.2 Up Translation

Input signals can be up translated using the SN54SC4T08-SEP. The voltage applied at V_{CC} will determine the output voltage and the input thresholds as described in the *Recommended Operating Conditions* and *Electrical Characteristics* tables. When connected to a high-impedance input, the output voltage will be approximately V_{CC} in the HIGH state, and 0 V in the LOW state.

The inputs have reduced thresholds that allow for input HIGH state levels which are much lower than standard values. For example, standard CMOS inputs for a device operating at a 5-V supply will have a $V_{IH(MIN)}$ of 3.5 V. For the SN54SC4T08-SEP, $V_{IH(MIN)}$ with a 5-V supply is only 2 V, which would allow for up-translation from a typical 2.5-V to 5-V signals.

Ensure that the input signals in the HIGH state are above $V_{IH(MIN)}$ and input signals in the LOW state are lower than $V_{IL(MAX)}$ as shown in \boxtimes 8-2.

Up Translation Combinations are as follows:

- 1.8-V V_{CC} Inputs from 1.2 V
- 2.5-V V_{CC} Inputs from 1.8 V
- 3.3-V V_{CC} Inputs from 1.8 V and 2.5 V
- 5.0-V V_{CC} Inputs from 2.5 V and 3.3 V

8.4 Device Functional Modes

表 8-1 provides the functions for the SN54SC4T08-SEP.

表 8-1. Function Table

INP	JTS ⁽¹⁾	ОИТРИТ			
A	В	Y (1)			
Н	Н	Н			
L	Х	L			
X	L	L			

(1) H = high voltage level, L = low voltage level, X = do not care, Z = high impedance

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9 Application and Implementation

注

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9.1 Application Information

In this application, three 2-input AND gates are combined to produce a 4-input AND gate function as shown in *Typical Application Block Diagram*. The fourth gate can be used for another application in the system, or the inputs can be grounded and the channel left unused.

The SN54SC4T08-SEP is used to directly control the RESET pin of a motor controller. The controller requires four input signals to all be HIGH before being enabled, and should be disabled in the event that any one signal goes LOW. The 4-input AND gate function combines the four individual reset signals into a single active-low reset signal.

9.2 Typical Application

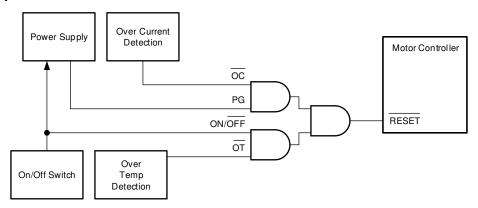


図 9-1. Typical Application Block Diagram

9.2.1 Design Requirements

9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN54SC4T08-SEP plus the maximum static supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current that is provided by the positive supply source. Be sure to not exceed the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN54SC4T08-SEP plus the maximum supply current, I_{CC}, listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Be sure to not exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.



The SN54SC4T08-SEP can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50 pF.

The SN54SC4T08-SEP can drive a load with total resistance described by $R_L \ge V_O / I_O$, with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in *CMOS Power Consumption and Cpd Calculation*.

Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.

注意

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

9.2.1.2 Input Considerations

Input signals must cross $V_{IL(max)}$ to be considered a logic LOW, and $V_{IH(min)}$ to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either V_{CC} or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the SN54SC4T08-SEP (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A 10-k Ω resistor value is often used due to these factors.

The SN54SC4T08-SEP has CMOS inputs and thus requires fast input transitions to operate correctly, as defined in the *Recommended Operating Conditions* table. Slow input transitions can cause oscillations, additional power consumption, and reduction in device reliability.

Refer to the *Feature Description* section for additional information regarding the inputs for this device.

9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OL} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Product Folder Links: SN54SC4T08-SEP

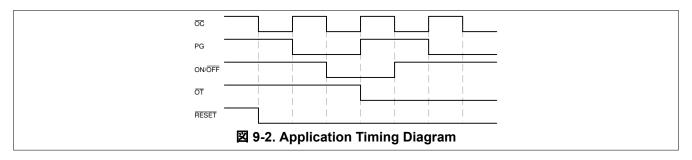
Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to the Feature Description section for additional information regarding the outputs for this device.

9.2.2 Detailed Design Procedure

- Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the *Layout* section.
- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit; by design, however, the limit will optimize performance. This can be accomplished by providing short, appropriately sized traces from the SN54SC4T08-SEP to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)}) \Omega$, which will prevent the maximum output current from the *Absolute Maximum Ratings* from being violated. Most CMOS inputs have a resistive load measured in M Ω ; much larger than the minimum calculated previously.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, *CMOS Power Consumption and Cpd Calculation*.

9.2.3 Application Curves



9.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in the following layout example.

9.4 Layout

9.4.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.



9.4.2 Layout Example

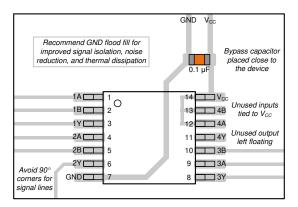


図 9-3. Example Layout for the SN54SC4T08-SEP

10 Device and Documentation Support

10.1 Documentation Support

10.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, CMOS Power Consumption and Cpd Calculation application report
- Texas Instruments, Implications of Slow or Floating CMOS Inputs application report

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11 Mechanical, Packaging, and Orderable Information

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
SN54SC4T08MPWTSEP	Active	Production	TSSOP (PW) 14	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SC08SEP
SN54SC4T08MPWTSEP.A	Active	Production	TSSOP (PW) 14	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SC08SEP
V62/23620-01XE	Active	Production	TSSOP (PW) 14	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SC08SEP

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

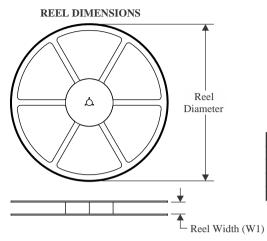
⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

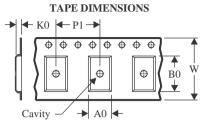
⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

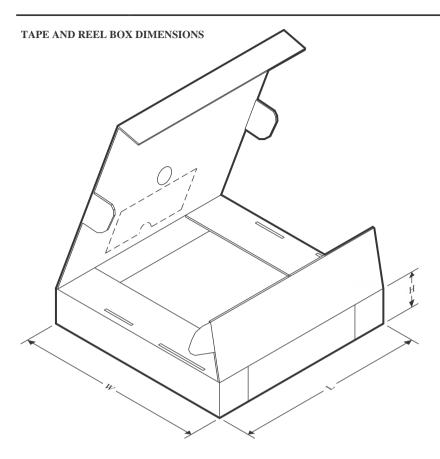


*All dimensions are nominal

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN54SC4T08MPWTSEP	TSSOP	PW	14	250	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

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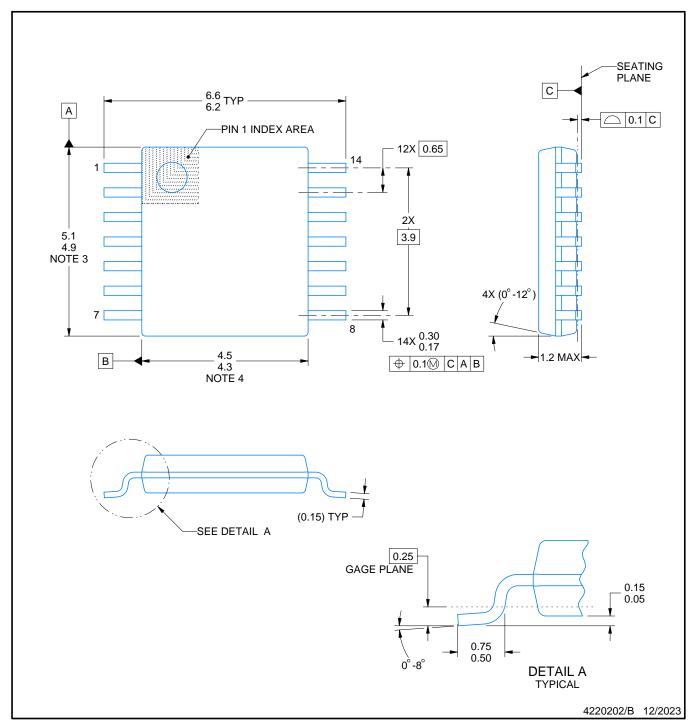


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN54SC4T08MPWTSEP	TSSOP	PW	14	250	353.0	353.0	32.0



SMALL OUTLINE PACKAGE



NOTES:

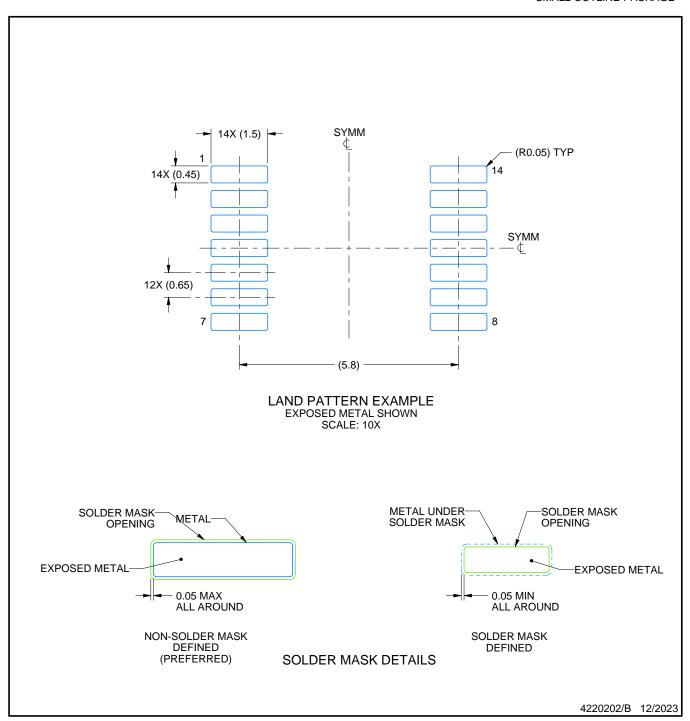
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



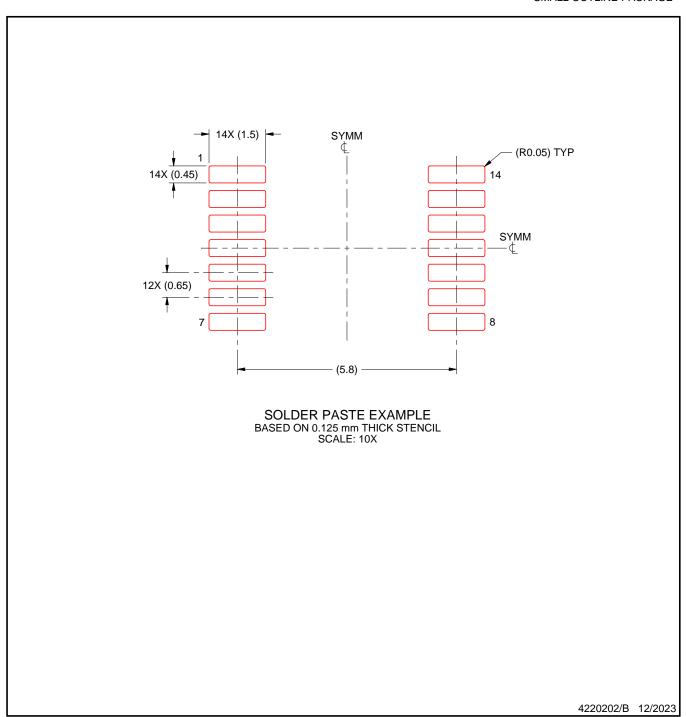
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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